



Subject card

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|---|---|--|--|-------------------------------------|--|------------|-----|
| Subject name and code | Metrology, PG_00047552 | | | | | | |
| Field of study | Automatic Control, Cybernetics and Robotics | | | | | | |
| Date of commencement of studies | October 2020 | Academic year of realisation of subject | | | 2020/2021 | | |
| Education level | first-cycle studies | Subject group | | | Obligatory subject group in the field of study | | |
| Mode of study | Full-time studies | Mode of delivery | | | at the university | | |
| Year of study | 1 | Language of instruction | | | Polish | | |
| Semester of study | 2 | ECTS credits | | | 1.0 | | |
| Learning profile | general academic profile | Assessment form | | | assessment | | |
| Conducting unit | Department of Metrology and Optoelectronics -> Faculty of Electronics, Telecommunications and Informatics | | | | | | |
| Name and surname of lecturer (lecturers) | Subject supervisor | | dr inż. Sylwia Babicz-Kiewlicz | | | | |
| | Teachers | | dr inż. Sylwia Babicz-Kiewlicz | | | | |
| Lesson types and methods of instruction | Lesson type | Lecture | Tutorial | Laboratory | Project | Seminar | SUM |
| | Number of study hours | 15.0 | 0.0 | 0.0 | 0.0 | 0.0 | 15 |
| | E-learning hours included: 0.0 | | | | | | |
| Learning activity and number of study hours | Learning activity | Participation in didactic classes included in study plan | | Participation in consultation hours | | Self-study | SUM |
| | Number of study hours | 15 | | 1.0 | | 9.0 | 25 |
| Subject objectives | The aim is introduction to : the essence of measurement, units and standards, methods of measurement, analysis of measurement uncertainty, basic instruments for measurement of electrical quantities. | | | | | | |
| Learning outcomes | Course outcome | | Subject outcome | | Method of verification | | |
| | [K6_W03] Knows and understands, to an advanced extent, the construction and operating principles of components and systems related to the field of study, including theories, methods and complex relationships between them and selected specific issues - appropriate for the curriculum | | Zna budowę oraz właściwości metrologiczne przyrządów do pomiaru podstawowych wielkości elektrycznych. Zna zasady działania przetworników analogowo/cyfrowych. Zna metody konstruowania systemów pomiarowych. | | [SW1] Assessment of factual knowledge | | |
| | [K6_W02] Knows and understands, to an advanced extent, selected laws of physics and physical phenomena as well as methods and theories explaining the complex relationships between them, constituting the basic general knowledge in the field of technical sciences related to the field of study | | Knows basic metrology terms. Knows the methods of measurement. Strictly defines the measurand (menzurand). Presents the results of measurements according to the recommendations of the International System of Units SI, using correct designations and prefixes to form multiple and aliquot units of measurement. Analyses systematic errors in direct and indirect measurements. Knows the causes of measurement uncertainty and how to minimise it during measurement. Evaluates the uncertainty of Type A and Type B methods of measurement. | | [SW1] Assessment of factual knowledge | | |
| Subject contents | 1. Introduction, basic metrological terms, classification of measurement methods 2. Measurement errors, types of errors: systematic, random, gross 3. Permanent-magnet moving-coil instrument and its application 4. Digital methods of low and high frequency measurements 5. Digital methods of time-interval and phase measurements 6. Dual-slope integration ADC 7. Immunity of integration ADCs from disturbances 8. Flash and subranging ADC 9. Digital multimeters: architecture, resistance to voltage converter, current to voltage converter, multiterminal inputs 10. AC voltage measurements, waveform parameters, average value, peak value and RMS measurements 11. Oscilloscope: architecture, principles of operation 12. Measurements of voltage, frequency, phase, parameters of pulse, display of device characteristics 13. Measurement uncertainty 14. Measurement methods of impedance parameters R, L, C, Z 15. Measuring systems and virtual instruments. | | | | | | |

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| Prerequisites and co-requisites | No requirements | | |
| Assessment methods and criteria | Subject passing criteria | Passing threshold | Percentage of the final grade |
| | Colloquium | 50.0% | 100.0% |
| Recommended reading | Basic literature | 1. Dusza J. : Podstawy miernictwa. OWPW, Warszawa 2002. 2. Lisowski M.: Podstawy metrologii, OWPW, Wrocław 2011. 3. Tumański S.: Technika pomiarowa, WNT, Warszawa 2007. 4. Kamieniecki A.: Współczesny oscyloskop. Budowa i pomiary, Wydawnictwo btc, Legionowo 2009. 5. Stabrowski M. : Cyfrowe przyrządy pomiarowe. Wyd. Naukowe PWN, Warszawa 2002. 6. Zięba A.: Analiza danych w naukach ścisłych i technice, PWN, Warszawa 2013. | |
| | Supplementary literature | No requirements | |
| | eResources addresses | | |
| Example issues/ example questions/ tasks being completed | <p>1 Two voltmeters could be used to measure the voltage $U = 12\text{ V}$. The first was a class 0.5 laboratory voltmeter with a measuring range of 60 V, and the second was a class 1.5 blackboard voltmeter with a measuring range of 15 V. Which voltmeter allowed the voltage value to be determined with less error?2) What is the measured frequency if 3587 pulses were counted in the 10 ms gate-opening time of the frequency meter.3. a frequency meter, normally operating with an internal reference frequency source of 1 MHz, was used with an external reference generator of 4 MHz. How should the frequency measurement results be corrected: (a) multiply by 4, (b) multiply by 2, (c) divide by 4.4. represent in the figure the voltage waveform that occurs at the output of the integrator in an A/D converter with double integration processing. Mark with "a" the time interval in which the reference voltage is integrated, with "b" the time interval in which the measured voltage is integrated, with "c" the time interval proportional to the measured voltage, with "d" the moment when the state of the comparator output changes, with "e" the moment when the counter overflows, with "f" the time interval which is to be equal to 20 ms to ensure immunity of the converter to mains frequency interference.The Y channel of the oscilloscope has a bandwidth of 40 MHz. What is the rise time of the step response of the oscilloscope. What is the rise time of the pulse you will read from the screen of this oscilloscope if you are testing a pulse whose rise time is 20 ns.6. The uncertainty of the voltage measurement is expressed in the multimeter specification as $\pm(1\%+2\text{ digits})$ and the reading is 1.200 V. Calculate the uncertainty of the voltage measurement.7 Explain the meaning of the abbreviations read from the face plate of the multimeter: AC, DC, 2W, 4W.8. Express the voltage ratios in dB: $U1/U2 = 103, 1, 10^{-2}$.9. give the rms and peak-to-peak value of the voltage in a domestic power network.10. Why is a four-wire connection between a resistor and a measuring instrument used when measuring small resistances?</p> | | |
| Work placement | Not applicable | | |